

SLOVENSKI STANDARD oSIST prEN IEC 61508-6:2025

01-maj-2025

Funkcijska varnost električnih/elektronskih/elektronsko programirljivih varnostnih sistemov - 6. del: Smernice za uporabo IEC 61508-2 in IEC 61508-3 (glej Funkcijska varnost in IEC 61508)

Functional safety of electrical/electronic/programmable electronic safety-related systems - Part 6: Guidelines on the application of IEC 61508-2 and IEC 61508-3 (see Functional Safety and IEC 61508)

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Sécurité fonctionnelle des systèmes électriques / électroniques / électroniques programmables relatifs à la sécurité - Partie 6: Lignes directrices pour l'application de la cei 61508-2 et de la cei 61508-3

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industrijskih postopkov measurement and control

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65A/1171/CDV

COMMITTEE DRAFT FOR VOTE (CDV)

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SECRETARIAT:	SECRETARY:
United Kingdom	Ms Stephanie Lavy
OF INTEREST TO THE FOLLOWING COMMITTEES:	HORIZONTAL FUNCTION(S):
TC 8,TC 9,TC 22,TC 31,TC 44,TC 45,TC 56,TC 61,TC 62,TC 65,SC 65B,SC 65C,SC 65E,TC 66,TC 72, TC 77,TC 80,TC 108,SyC AAL,SyC SM,SC 41	
ASPECTS CONCERNED:	
Safety	
SUBMITTED FOR CENELEC PARALLEL VOTING	□ NOT SUBMITTED FOR CENELEC PARALLEL VOTING
Attention IEC-CENELEC parallel voting	
The attention of IEC National Committees, members of CENELEC, is drawn to the fact that this Committee Draft for Vote (CDV) is submitted for parallel voting.	lards.iteh.ai) t Preview
The CENELEC members are invited to vote through the CENELEC online voting system.	

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TITLE:

Functional safety of electrical/electronic/programmable electronic safety-related systems - Part 6: Guidelines on the application of IEC 61508-2 and IEC 61508-3 (see Functional Safety and IEC 61508)

PROPOSED STABILITY DATE: 2027

NOTE FROM TC/SC OFFICERS:

"Due to committee meetings planned at the end of May in Pisa, Italy, it is appreciated to voluntarily submit comments on this Part of the IEC 61508 series by 2025-05-12 already. Of course, there will be all comments accepted for consideration be the committee arriving within the official circulation period, but it will help the committee for starting their work on the project phase."

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

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FUNCTIONAL SAFETY OF ELECTRICAL/ELECTRONIC/ PROGRAMMABLE ELECTRONIC SAFETY-RELATED SYSTEMS –

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FOREWORD

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- 187 IEC 61508-6 has been prepared by subcommittee 65A: System aspects, of IEC technical committee 65: Industrial-process measurement, control and automation.
- This third edition cancels and replaces the second edition published in 2010. This edition constitutes a technical revision.
- This edition includes the following significant technical changes with respect to the previous edition (the following list does refer to this document; other parts do mention specific further details):
 - a) Document was upgraded to the 2024 version of the ISO/IEC Directives; this does introduce a significant number of editorial changes, clause renumbering and rewording of the information provided in Notes;